



*Industrial Computing Platform Partner*

# **AEC-6510 (GENE-5315)**

**With CFD**

## **Temperature Cycle Test Report**

**Report NO: 08P020012**

Issued by: **Rex Chang** / **06/13/2008**  
\_\_\_\_\_  
Test Engineer Date

Reviewed by: **Wenyuan Yang** / **06/13/2008**  
\_\_\_\_\_  
Manager Date

# Test item list

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Num	Item	Spec
1.	Control Box:	AEC- 6510
	1. Main Board	AAEON GENE-5315 Rev. B1.0 Compact Board (BIOS: 1.0)
	2. CPU	AMD Geode LX800 / 500MHz
	3. Memory	Apacer 512MB / HY5DU1216220TP-J / DDR333
	4. Power Module	AAEON PO2D A1.1
	5. Industrial CFD	Transcend 4GB
	6. Adapter	SINPRO MPU50-105

# Temperature cycle test

**Test Date:** 06-11~13-2008

**Test Product:** AEC-6510

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

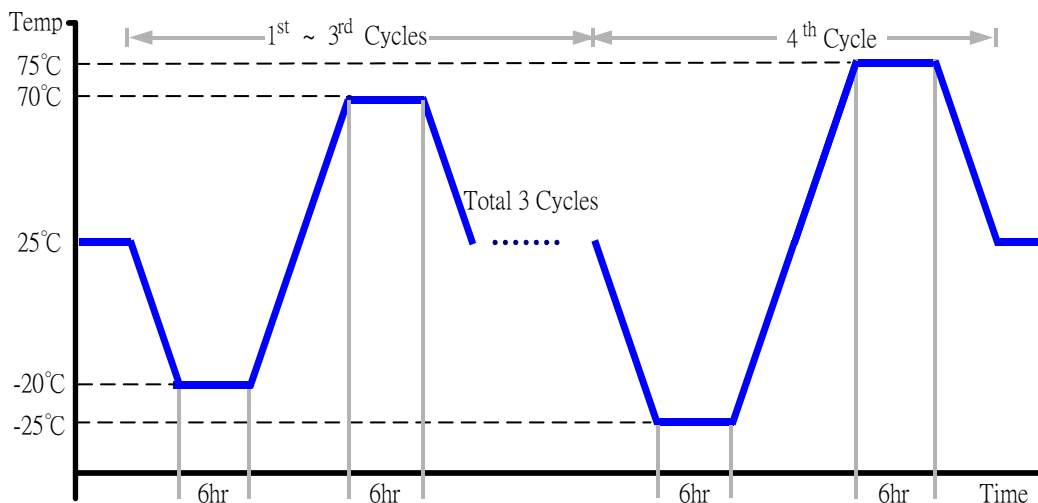
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6487KT

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/13/07  
Serial Number: 12A323190

**Test Condition:**

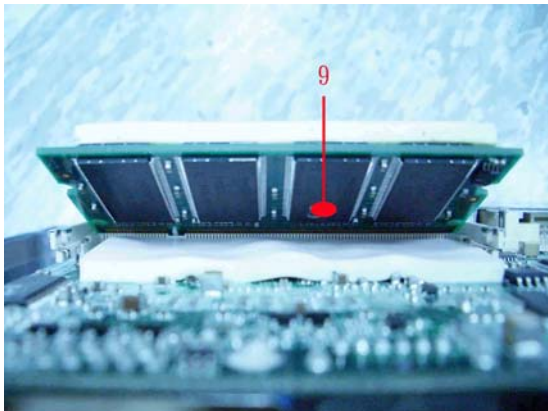
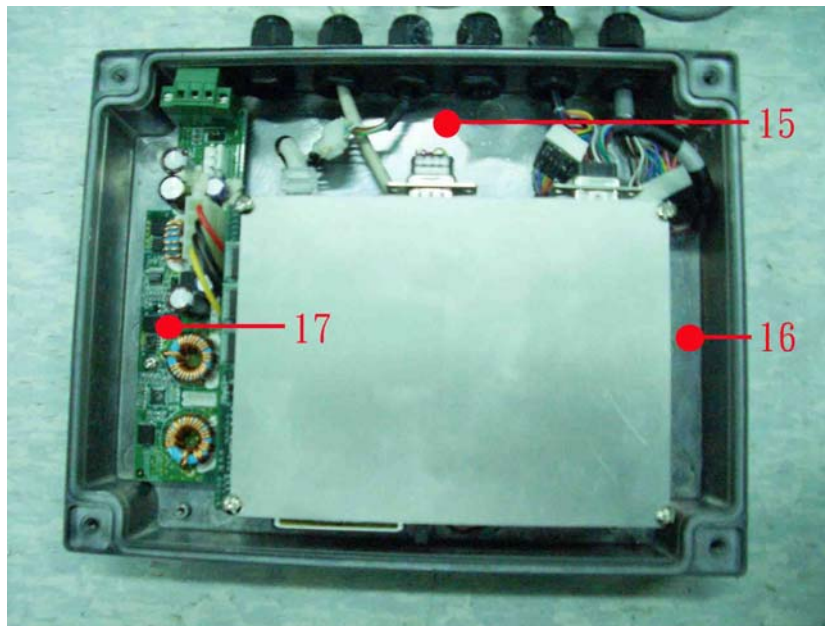
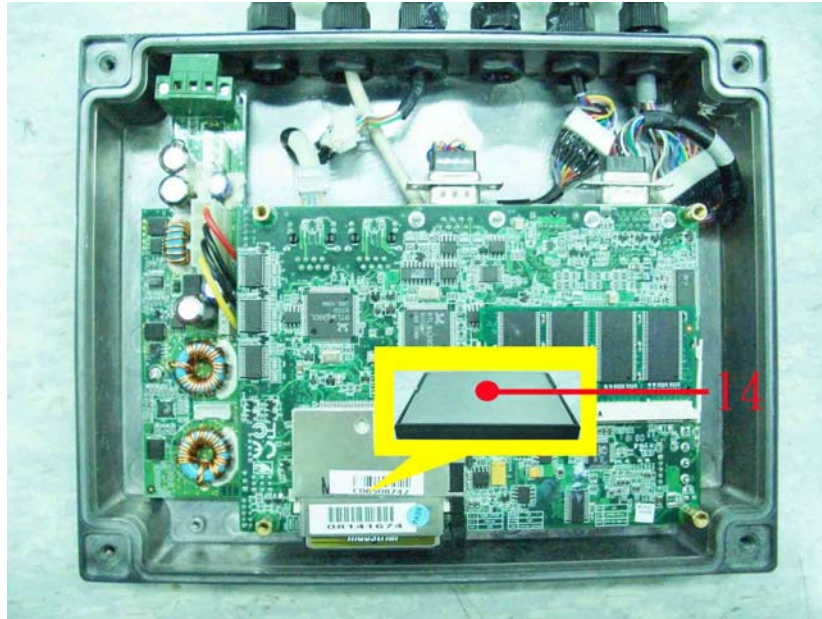
1. Test Low Temperature: -20°C (1~3 cycles)  
-25°C (4<sup>th</sup> cycle)
2. Test High Temperature: 70°C (1~3 cycles)  
75°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



# Temperature cycle test

## Terminal Recorder:

Measuring Thermal Couple Position :



# Temperature cycle test

## Thermal profile data:

### AEC-6510 (GENE-5315)

Point	Temp. Stage(°C)	Spec	70	25	-20
<b>GENE-5315</b>					
01. U13 - (TF)IC.SMD.SSOP28.Clock Generator.ICS.MK1491-09FLN		100	88.7	43.7	-1.3
02. CPU		85	80.9	35.9	-9.1
03. U7 - (TF)IC.SMD SOP 8P.Clock Output Buffer.ICS.ICS9112M-16LF-T		100	86.5	41.5	-3.5
04. U1 - (TF)IC.SMD.QFP128P Super I/O.ITE.IT8712F/KX-L		100	78.6	33.6	-11.4
05. U8 - (TF)Flash PLCC BIOS.1M.(Memory.SST.49LF008A-33-4C-NHE)		110	82.5	37.5	-7.5
06. U37 - (TF)IC.SMD.TSSOP56.FlatLink Transmitter.TI.SN75LVDS83		100	80.6	35.6	-9.4
07. U33 - (TF)IC.SMD.LQFP 100P PCI Ethernet Chip.RELTEK.RTL8139DL		100	85.6	40.6	-4.4
08. U10 - (TF)IC.SMD.LQFP 100P PCI Ethernet Chip.RELTEK.RTL8139DL		100	83.4	38.4	-6.6
09. Memory		85	82.4	37.4	-7.6
10. U24 - (TF)IC.SMD.2 Channel Audio Codec.Realtek.ALC203-LF		100	92.5	47.5	2.5
<b>PO2D A1.1</b>					
11. U2 - (TF) Regulator.Vin 3.5-36V.LINEAR.LTC3728EUH#PBF		85	81.0	36.0	-9.0
12. Q7 - (TF)PWR.N-Channel 30V MOSFET.VISHAY.SI4410BDY-T1-E3v		125	79.1	34.1	-10.9
13. U1 - (TF)PWR.SSOP16 MOSFET.LINEAR-TECHNOLOGY.LTC1778EGN		110	77.9	32.9	-12.1
14. CFD		85	80.1	35.1	-9.9
15. Control Box Internal Air Temperature - 1		N/A	75.6	30.6	-14.4
16. Control Box Internal Air Temperature - 2		N/A	75.4	30.4	-14.6
17. Control Box Internal Air Temperature - 3		N/A	78.0	33	-12
18. Control Box External Surface		N/A	72.9	27.9	-17.1
19. Chamber Air Temperature		N/A	69.8	24.8	-20.2
<b>The description in red states which temperature is over the specification of the device.</b>					

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-6510)

## Test Result:

No problem was found during the temperature operation cycle test.

**Test Date:** 06-02~04-2008

**Test Product:** AEC-6510.

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 80°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test Pro 4.0
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6510)

**Test Result:**

No problem was found after the high temperature storage test.

**Test Date:** 06-04~06-2008

**Test Product:** AEC-6510

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: -30°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test Pro 4.0
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6510)

**Test Result:**

No problem was found after the low temperature storage test.

**Test Date:** 06-06~09-2008

**Test Product:** AEC-6510.

**Test Site:** AAEON QA Internal Lab.

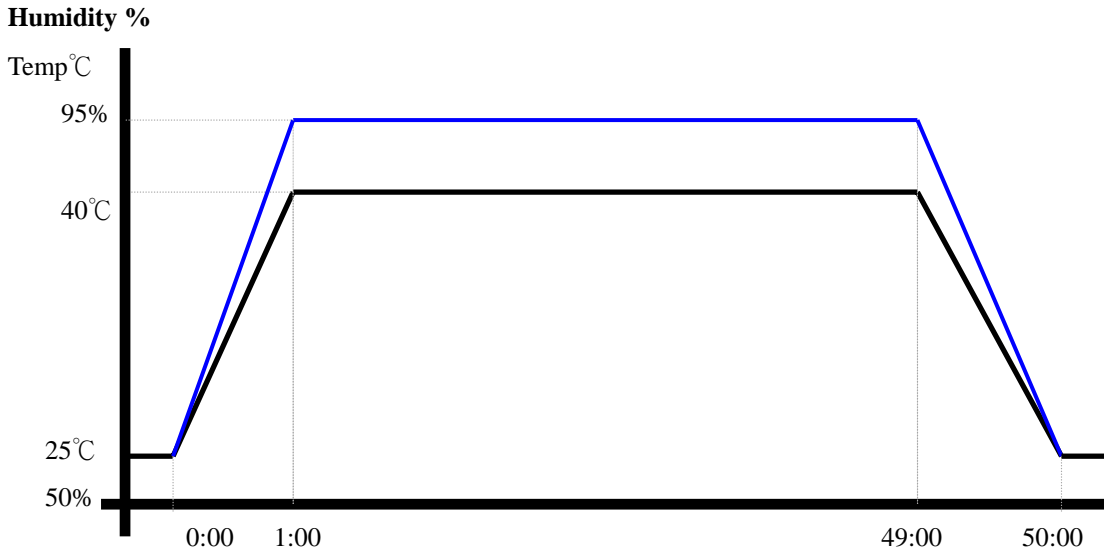
**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test Pro 4.0
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6510)

**Test Result:**  
No problem was found after the humidity storage test.



# Cold start and hot start test

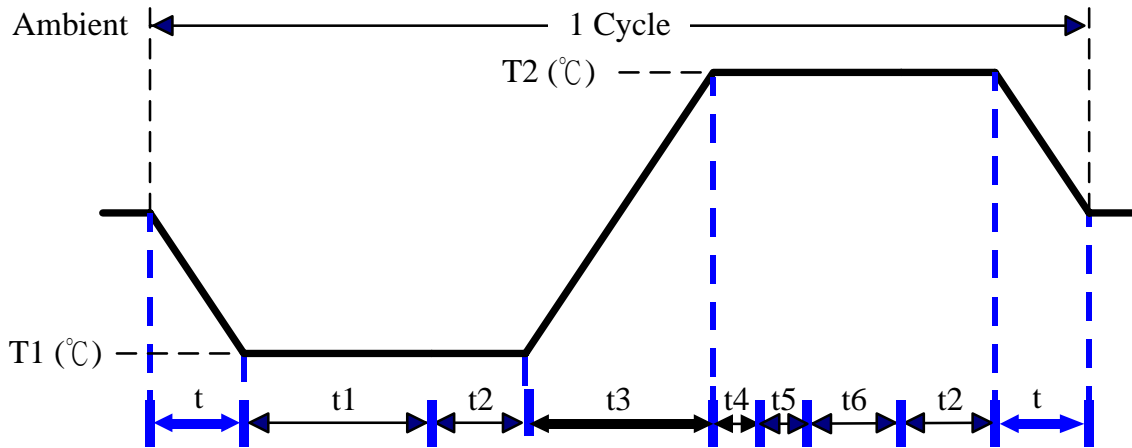
**Test Date:** 06-09~10-2008

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6487KT

**Test Condition:**



Parameters	Description
T1	-25°C
T2	75°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope  
t , t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 3 times  
Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.